

INTERNATIONAL SEARCH REPORT

International Application No

/EP2004/010839

A. CLASSIFICATION OF SUBJECT MATTER
H01J49/38

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
HOIJ

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal , WPI Data

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication where appropriate of the relevant passages	Relevant to claim No
X	<p>VARTANIAN ET AL: "High performance fourier transform ion cyclotron resonance mass spectrometry via a single trap electrode"</p> <p>JOURNAL OF THE AMERICAN SOCIETY FOR MASS SPECTROMETRY, ELSEVIER SCIENCE INC, US, vol. 6, no. 9, September 1995 (1995-09), pages 812-821, XP005172324</p> <p>ISSN: 1044-0305</p> <p>abstract</p> <p>page 814; figure 1</p> <p>page 820, left-hand column</p> <p>-----</p> <p>-/--</p>	<p>1,6-13,</p> <p>15,</p> <p>18-25,</p> <p>27-31</p>

☒ Further documents are listed in the continuation of box C

D Patent family members are listed in annex

* Special categories of cited documents

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier document but published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance, the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance, the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&" document member of the same patent family

Date of the actual completion of the international search

17 February 2006

Date of mailing of the international search report

06/03/2006

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tWEP2004/010839

C(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category	Citation of document, with indication, where appropriate of the relevant passages	Relevant to claim No
A	<p>SHENHENG G ET AL: "Ion traps for Fourier transform ion cyclotron resonance mass spectrometry: principles and design of geometric and electric configurations" INTERNATIONAL JOURNAL OF MASS SPECTROMETRY AND ION PROCESSES, ELSEVIER SCIENTIFIC PUBLISHING CO. AMSTERDAM, NL, vol. 146-14, 31 August 1995 (1995-08-31), pages 261-296, XP004036674 ISSN: 0168-1176 the whole document</p> <p>-----</p>	1-31
A	<p>BEU S C ET AL: "OPEN TRAPPED ION CELL GEOMETRIES FOR FOURIER TRANSFORM ION CYCLOTRON RESONANCE MASS SPECTROMETRY" INTERNATIONAL JOURNAL OF MASS SPECTROMETRY AND ION PROCESSES, ELSEVIER SCIENTIFIC PUBLISHING CO. AMSTERDAM, NL, vol. 112, no. 2/3, 15 January 1992 (1992-01-15), pages 215-230, XP000277845 ISSN: 0168-1176 the whole document</p> <p>-----</p>	1-31
A	<p>NIKOLAEV E N ET AL: "Analysis of harmonics for an elongated FTMS cell with multiple electrode detection" 20 December 1996 (1996-12-20), INTERNATIONAL JOURNAL OF MASS SPECTROMETRY AND ION PROCESSES, ELSEVIER SCIENTIFIC PUBLISHING CO. AMSTERDAM, NL, PAGE(S) 215-232 , XP004062773 ISSN: 0168-1176 the whole document</p> <p>-----</p>	1-31